

## General Description

The WSD3069DN56 is the highest performance trench N-ch and P-ch MOSFET with extreme high cell density, which provide excellent R<sub>DS(on)</sub> and gate charge for most of the synchronous buck converter applications.

The WSD3069DN56 meet the RoHS and Green Product requirement 100% EAS guaranteed with full function reliability approved.

## Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- 100% EAS Guaranteed
- Green Device Available

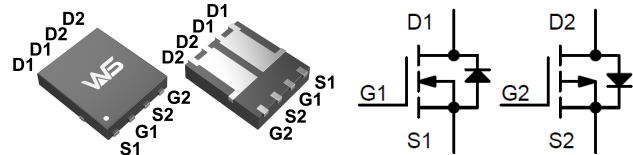
## Product Summary

BVDSS	R <sub>DS(on)</sub>	ID
30V	15mΩ	16A
-30V	15mΩ	-16A

## Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- CCFL Back-light Inverter

## DFN5X6C-8 Pin Configuration



## Absolute Maximum Ratings (T<sub>A</sub>= 25°C unless otherwise noted)

Symbol	Parameter	N Channl	P Channl	Unit	
V <sub>DSS</sub>	Drain-Source Voltage	30	-30	V	
V <sub>GSS</sub>	Gate-Source Voltage	±20	±20		
I <sub>D</sub>	Continuous Drain Current c	T <sub>C</sub> =25°C	16	-16	A
		T <sub>C</sub> =100°C	10.5	-12.5	
I <sub>DM</sub>	Pulsed Drain Current c	35	-65	A	
I <sub>DSM</sub>	Continuous Drain Current	T <sub>A</sub> =25°C	9.5	-11	A
		T <sub>A</sub> =70°C	7.5	-8.5	
P <sub>D</sub>	Maximum Power Dissipation B	T <sub>C</sub> =25°C	10	20	W
		T <sub>C</sub> =100°C	4	8	
P <sub>DSM</sub>	Maximum Power Dissipation A	T <sub>C</sub> =25°C	3.1	4.1	W
		T <sub>C</sub> =100°C	2	2.6	
I <sub>S</sub>	Diode Continuous Forward Current	T <sub>C</sub> =25°C	10	-16	A
E <sub>EAS</sub>	Single pulsed avalanche energy c	L=0.5mH	7	-36	mJ
I <sub>AS</sub>	Single pulsed avalanche Current	L=0.5mH	12	-27	A
T <sub>J</sub>	Maximum Junction Temperature	150	150	°C	
T <sub>STG</sub>	Storage Temperature Range	-55 to 150	-55 to 150		
R <sub>θJA</sub>	Thermal Resistance-Junction to Ambient AD	t≤10S	40	30	°C/W
		Steady Statec	70	65	°C/W
R <sub>θJC</sub>	Thermal Resistance-Junction to Case	21	6	°C/W	

**N-Channl Electrical Characteristics** ( $T_J = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=250\mu A$	30	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=24V, V_{GS}=0V$	-	-	1	$\mu A$
		$T_J=55^\circ C$	-	-	5	$\mu A$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=250\mu A$	1	1.5	2	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
$R_{DS(ON)}$	Drain-Source On-state Resistance	$V_{GS}=10V, I_{DS}=10A$	-	15	19.5	m $\Omega$
		$V_{GS}=4.5V, I_{DS}=5A$	-	18	24	
$R_G$	Gate Resistance	$F=1MHz, V_{GS}=0V, V_{DS}=0V$	-	-	2.8	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS}=0V, V_{DS}=15V,$ Frequency=1.0MHz	-	373	-	pF
$C_{oss}$	Output Capacitance		-	67	-	
$C_{riss}$	Reverse transfer capacitance		-	41	-	
$t_{d(ON)}$	Turn-on delay Time	$V_{GEN}=10V, V_{DD}=15V, R_G=3\Omega,$ $RL=1.5\Omega$	-	4.3	-	nS
$t_r$	Turn-on rise Time		-	2.8	-	
$t_{d(OFF)}$	Turn-off delay Time		-	15.8	-	
$t_f$	Turn-off rise Time		-	3	-	
$Q_g$	Total Gate Charge (10V)	$V_{DS}=15V, V_{GS}=10V, I_{DS}=10A$	-	7.1	-	nC
$Q_g$	Total Gate Charge (4.5V)		-	3.5	-	
$Q_{gs}$	Gate-Source Charge		-	1.2	-	
$Q_{gd}$	Gate-Drain Charge		-	1.6	-	
$V_{SD}$	Diode Forward Voltage	$I_{SD}=1A, V_{GS}=0V$	-	0.75	1	V
$t_{rr}$	Reverse Recovery Time	$I_{DS}=10A,$ $dI_{SD}/dt=500A/\mu s$	-	6	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	6.6	-	nC

A. The value of  $R_{\theta JA}$  is measured with the device mounted on 1in2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ C$ . The Power dissipation  $P_{DSM}$  is based on  $R_{\theta JA} t \leq 10s$  and the maximum allowed junction temperature of  $150^\circ C$ . The value in any given application depends on the user's specific board design.

B. The power dissipation  $P_D$  is based on  $T_{J(MAX)}=150^\circ C$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C. Single pulse width limited by junction temperature  $T_{J(MAX)}=150^\circ C$ .

D. The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $<300\mu s$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, rating, assuming a maximum junction temperature of  $T_{J(MAX)}=150^\circ C$ . The SOA curve provides a single pulse

G. The maximum current rating is package limited.

H. These tests are performed with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in a still air environment with  $T_A=25^\circ C$ .

**P-Channl Electrical Characteristics** ( $T_J = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Unit
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS}=0V, I_{DS}=-250A$	-30	-	-	V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=-24V, V_{GS}=0V$	-	-	-1	$\mu A$
		$T_J=55^\circ C$	-	-	-5	$\mu A$
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_{DS}=-250A$	1	1.5	2	V
$I_{GSS}$	Gate Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	-	-	$\pm 100$	nA
$R_{DS(ON)}$	Drain-Source On-state Resistance	$V_{GS}=-10V, I_{DS}=-9.7A$	-	15	20	m $\Omega$
		$V_{GS}=-4.5V, I_{DS}=-7A$	-	20	27	
$R_G$	Gate Resistance	$F=1MHz, V_{GS}=0V, V_{DS}=0V$	-	4	-	$\Omega$
$C_{iss}$	Input Capacitance	$V_{GS}=0V, V_{DS}=-15V,$ Frequency=1.0MHz	-	1040	-	pF
$C_{oss}$	Output Capacitance		-	180	-	
$C_{rss}$	Reverse transfer capacitance		-	125	-	
$t_{d(ON)}$	Turn-on delay Time	$V_{GEN}=-10V, V_{DD}=-15V, R_G=3\Omega,$ $RL=1.5\Omega$	-	10	-	nS
$t_r$	Turn-on rise Time		-	5.5	-	
$t_{d(OFF)}$	Turn-off delay Time		-	26	-	
$t_f$	Turn-off rise Time		-	9	-	
$Q_g$	Total Gate Charge	$V_{DS}=-15V, V_{GS}=-10V, I_{DS}=-$ $9.7A$	-	19	-	nC
$Q_g$	Total Gate Charge		-	9.6	-	
$Q_{gs}$	Gate-Source Charge		-	3.6	-	
$Q_{gd}$	Gate-Drain Charge		-	4.6	-	
$V_{SD}$	Diode Forward Voltage	$I_{SD}=-1A, V_{GS}=0V$	-	-0.75	-1.1	V
$t_{rr}$	Reverse Recovery Time	$I_{DS}=-9.7A,$ $dI_{SD}/dt=500A/\mu s$	-	11.5	-	ns
$Q_{rr}$	Reverse Recovery Charge		-	25	-	nC

N-Channl TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

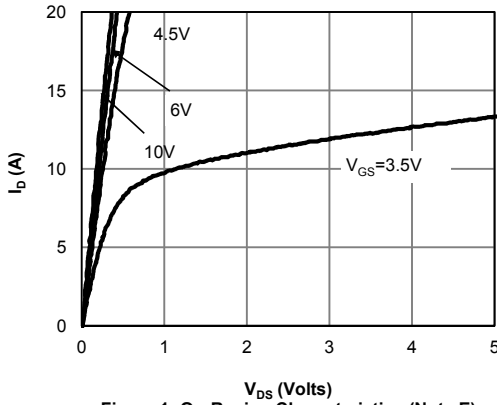


Figure 1: On-Region Characteristics (Note E)

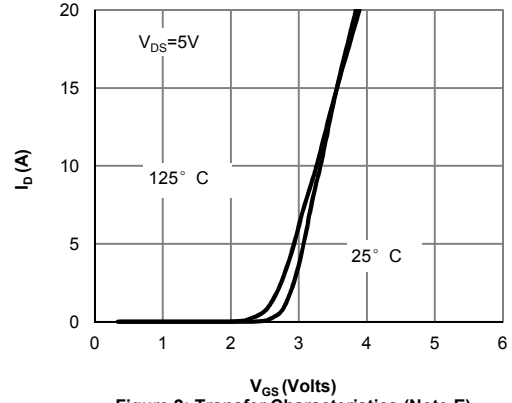


Figure 2: Transfer Characteristics (Note E)

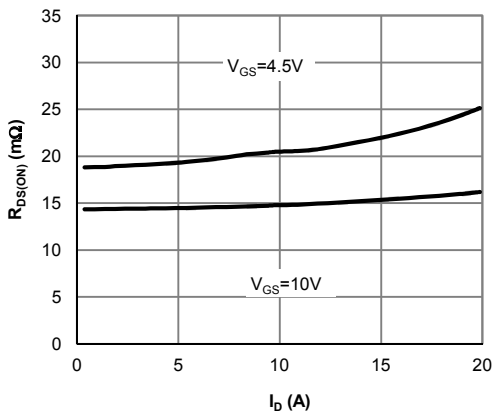


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

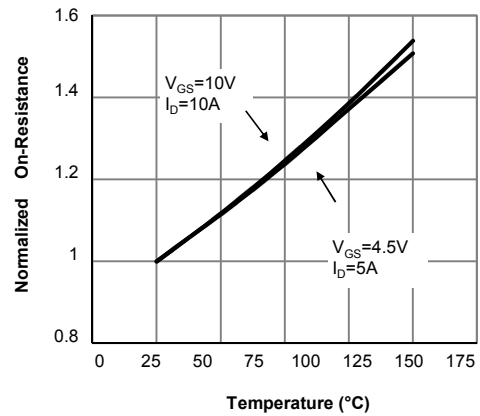


Figure 4: On-Resistance vs. Junction Temperature (Note E)

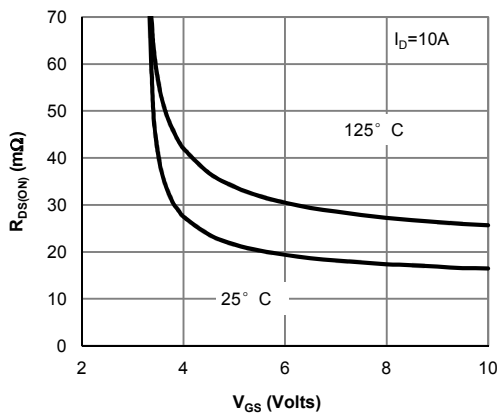


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

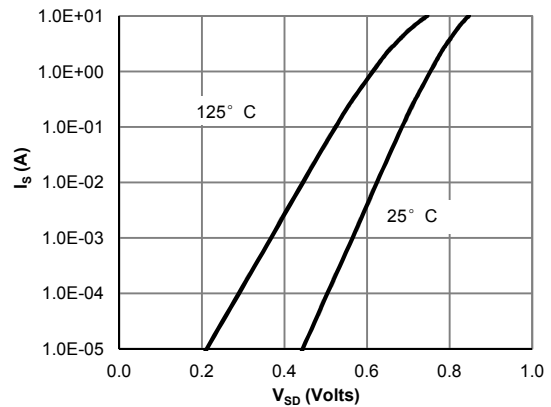


Figure 6: Body-Diode Characteristics (Note E)

N-Channl TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

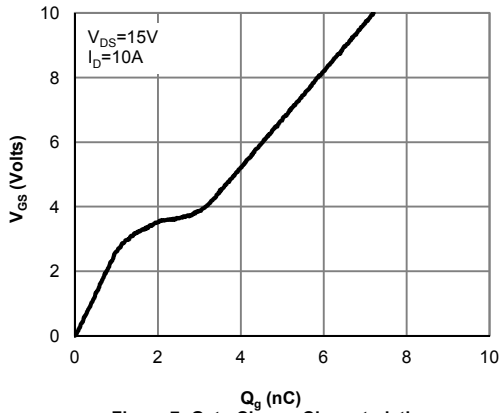


Figure 7: Gate-Charge Characteristics

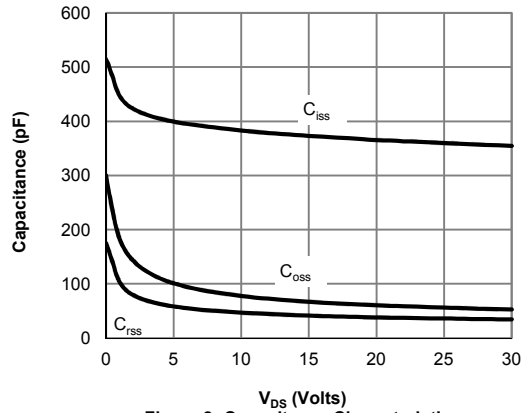


Figure 8: Capacitance Characteristics

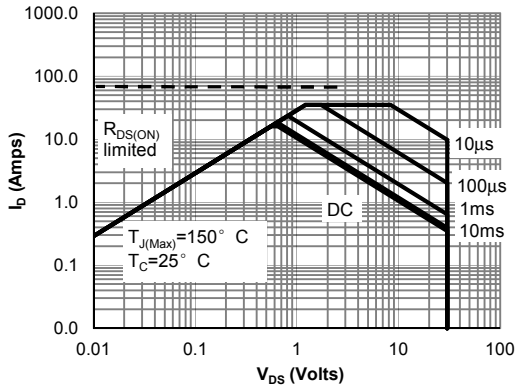


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

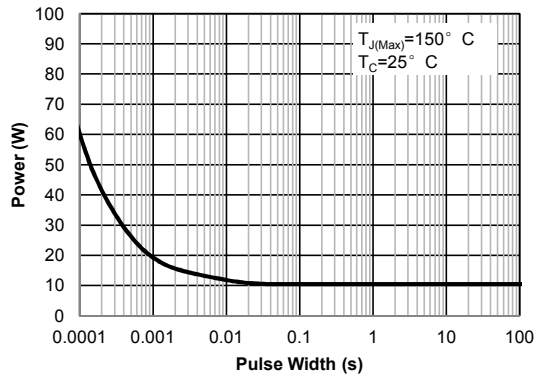


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

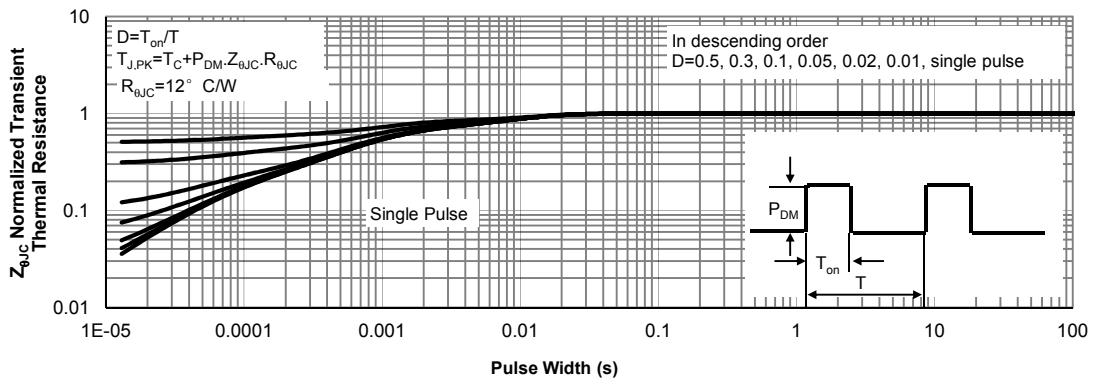


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

**N-Channl TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

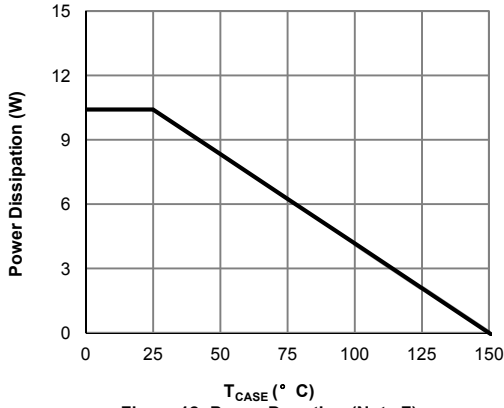


Figure 12: Power De-rating (Note F)

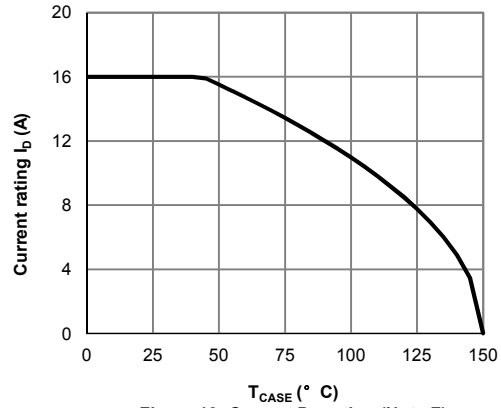


Figure 13: Current De-rating (Note F)

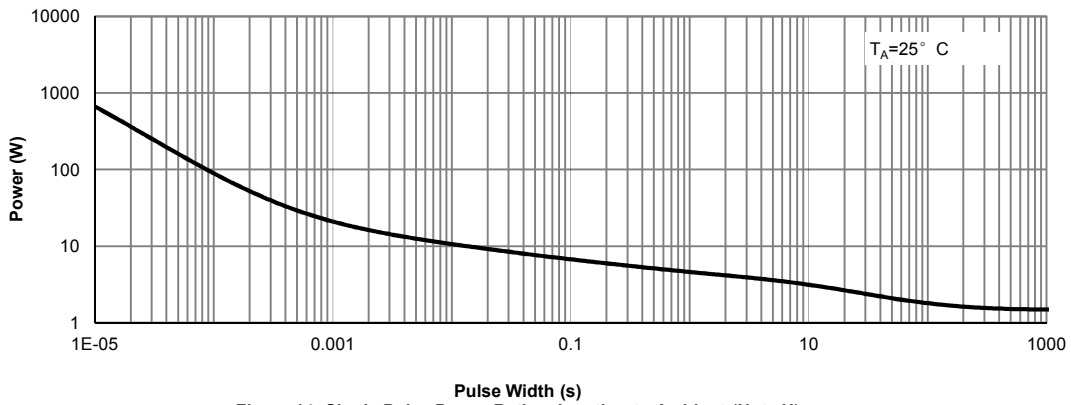


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

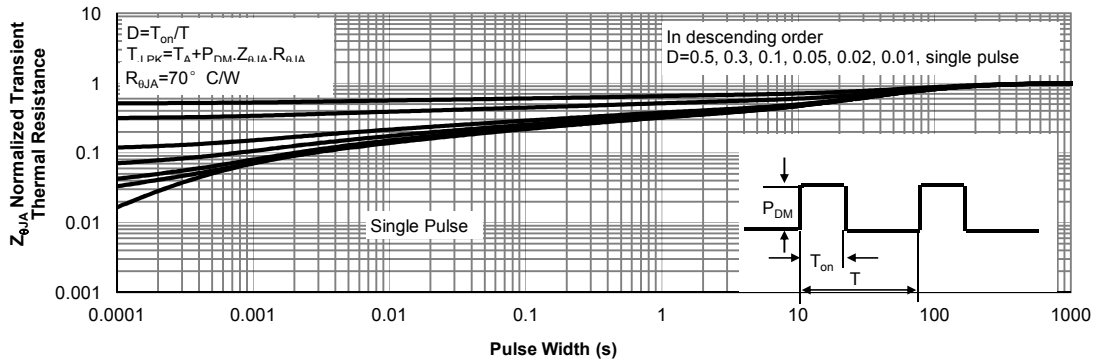


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)

**P-Channl TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

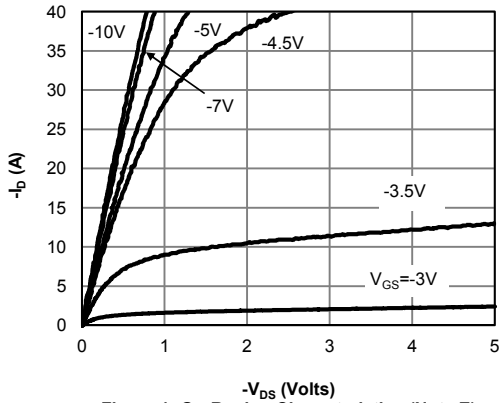


Figure 1: On-Region Characteristics (Note E)

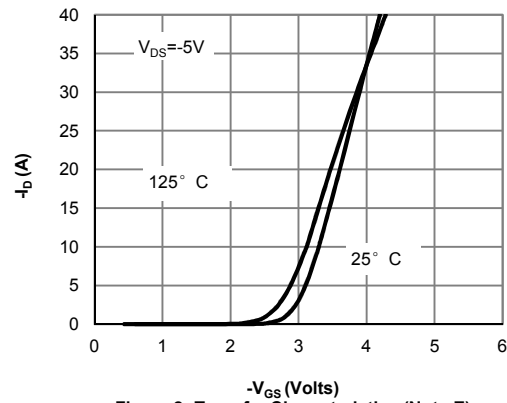


Figure 2: Transfer Characteristics (Note E)

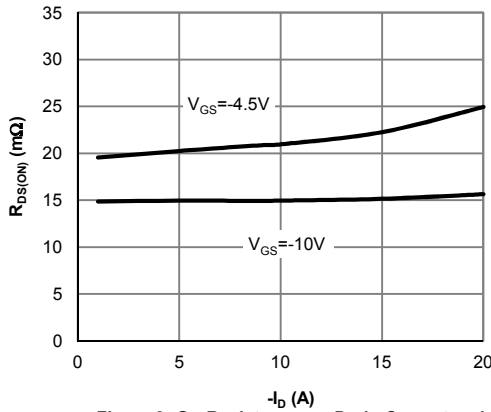


Figure 3: On-Resistance vs. Drain Current and Gate Voltage (Note E)

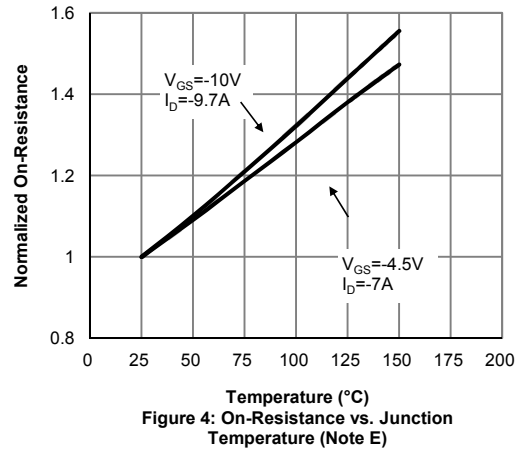


Figure 4: On-Resistance vs. Junction Temperature (Note E)

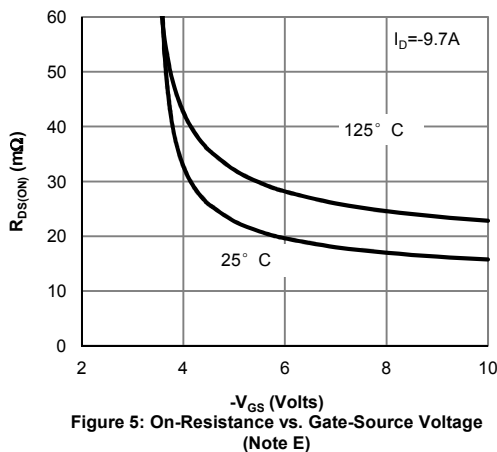


Figure 5: On-Resistance vs. Gate-Source Voltage (Note E)

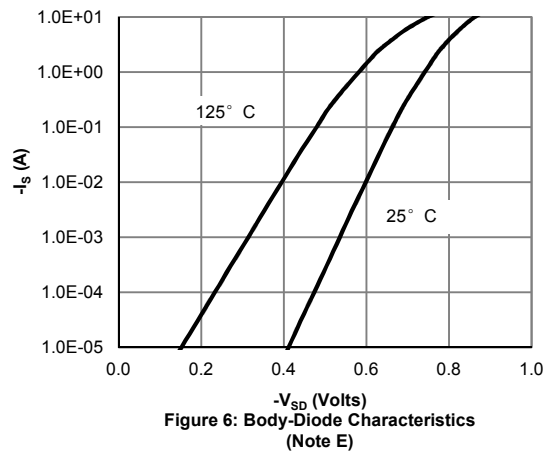


Figure 6: Body-Diode Characteristics (Note E)

**P-Channl TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

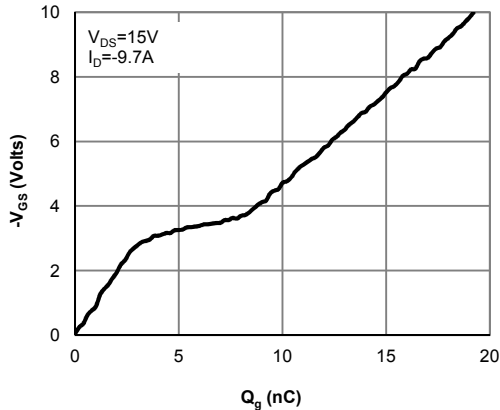


Figure 7: Gate-Charge Characteristics

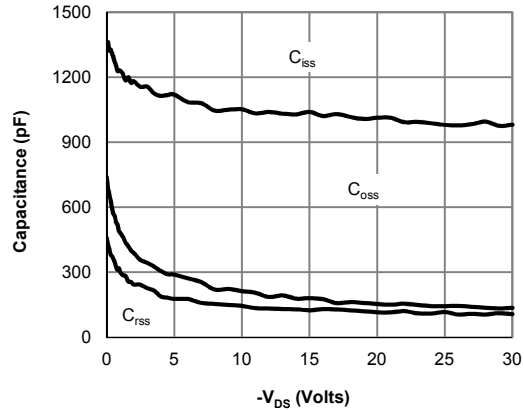


Figure 8: Capacitance Characteristics

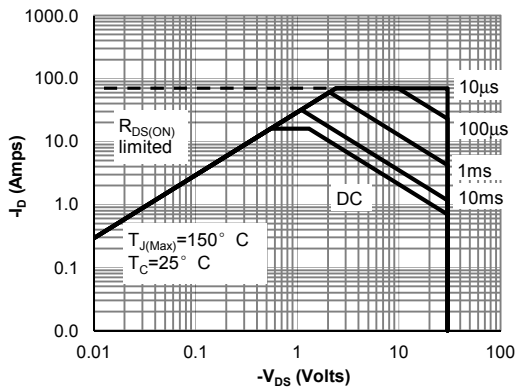


Figure 9: Maximum Forward Biased Safe Operating Area (Note F)

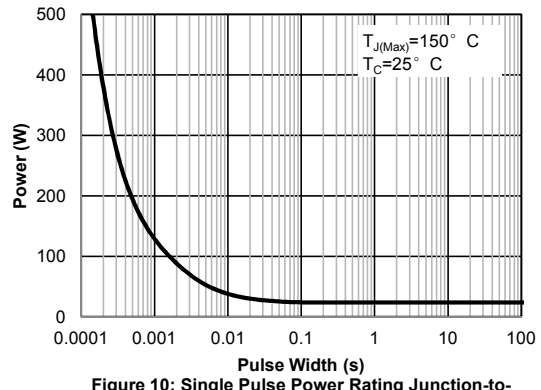


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

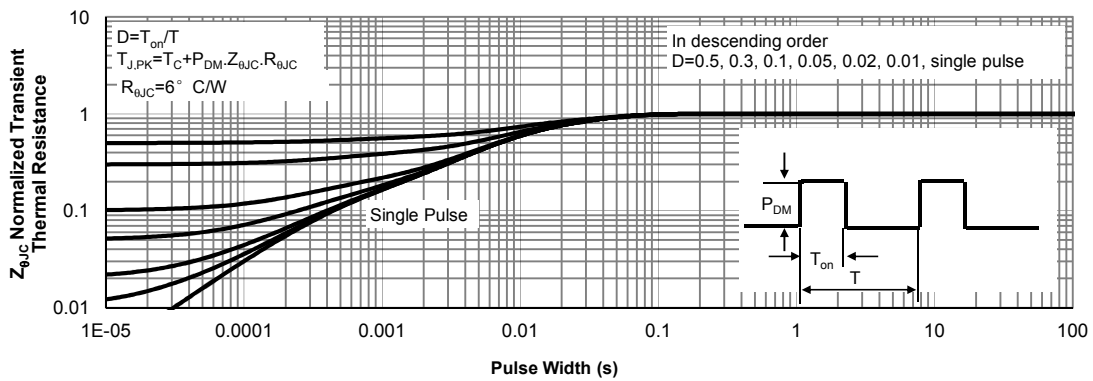


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)



P-Channl TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

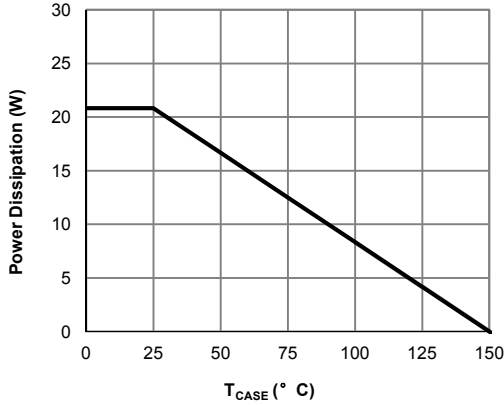


Figure 12: Power De-rating (Note F)

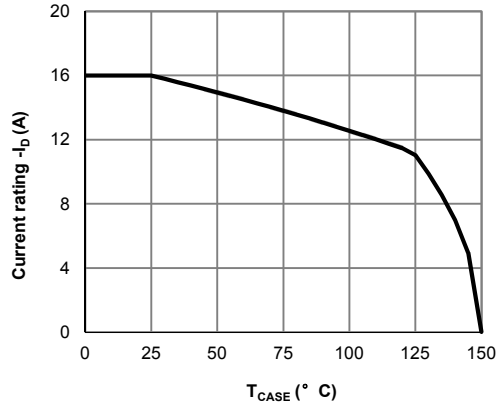


Figure 13: Current De-rating (Note F)

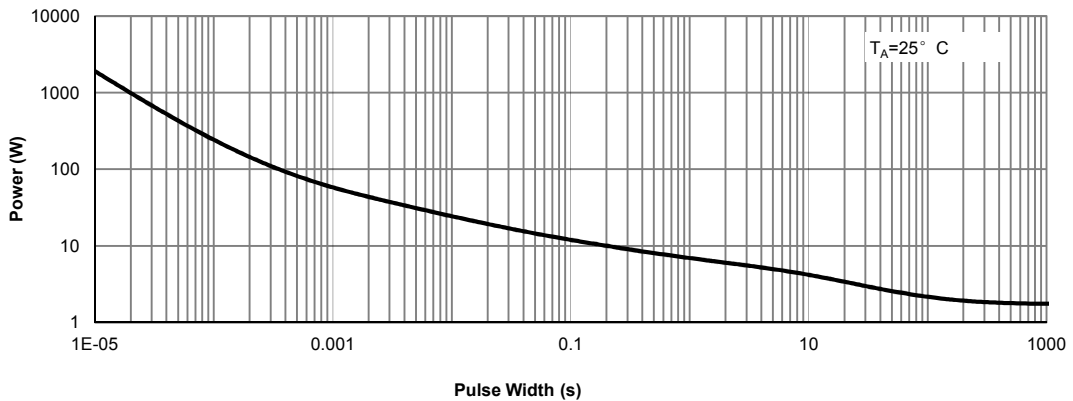


Figure 14: Single Pulse Power Rating Junction-to-Ambient (Note H)

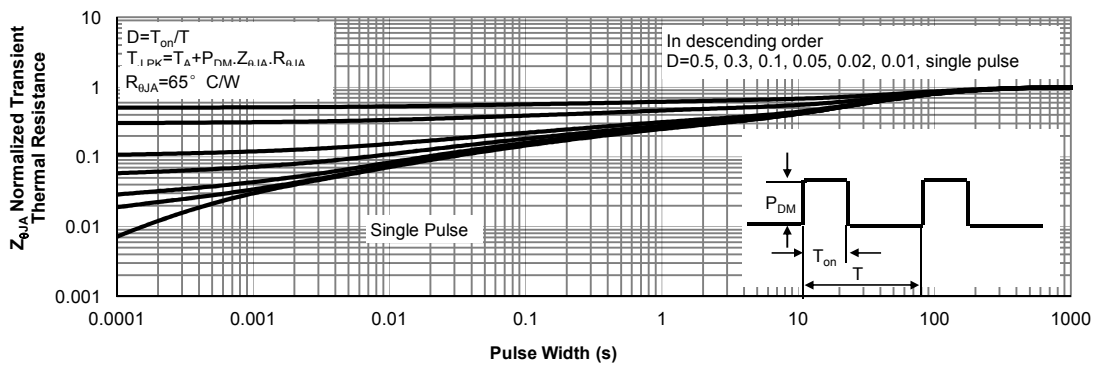


Figure 15: Normalized Maximum Transient Thermal Impedance (Note H)



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